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PRE-STANDARD

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Connectors for electrical and electronic equipment – Tests and measurements – Part 27-200: Additional specifications for signal integrity tests up to 2 000 MHz on IEC 60603-7 series connectors – Tests 27a to 27g

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CONTENTS

FOREWORD 8
1 Scope 10
2 Normative references 10
3 Terms and definitions 12
4 Overall test arrangement 12
4.1 General 12
4.2 Indirect-reference test fixtures 12
Annex A (normative) Indirect-reference test fixtures 13
A.1 General 13
A.2 Requirements 13
Annex B (normative) Measurement requirements (general) 14
B.1 General test configuration 14
B.2 Termination of a cable DUT to test system 14
B.2.1 General 14
B.2.2 Interconnections between the device under test (DUT) and the calibration plane 15
B.2.3 Test lead return loss requirements 15
B.2.4 Ground plane requirements 18
B.2.5 Network analyzer requirements 18
B.3 Measurement points and spacing 18
B.4 Impedance matching terminations 19
B.4.1 General 19
B.4.2 Resistor terminations 19
B.4.3 Termination return loss performance at the calibration plane 20
B.4.4 Termination TCL performance at the calibration plane 20
B.4.5 Calibration methods 20
B.4.6 Two-port calibration of the test system 21
B.4.7 One-port calibration of the test system 21
B.5 General calibration plane 21
B.5.1 General 21
B.5.2 Calibration references 22
B.5.3 50 Ω and 100 Ω calibration reference load requirements 22
B.5.4 Calibration reference load return loss requirement 23
B.5.5 Typical test equipment performance parameters 23
Annex C (normative) Cabling and component test procedures using baluns 24
C.1 Measurement test setup and apparatus 24
C.1.1 General 24
C.1.2 Balun terminations 24
C.1.3 Balun requirements 24
C.2 Testing of cabling 26
C.2.1 Cabling DC resistance 26
C.2.2 Return loss testing of cables and channels 27
C.2.3 Insertion loss of cables and channels 29
C.2.4 NEXT loss of cables and channels 30
C.2.5 FEXT loss of cables and channels 32
C.2.6 Cable and channel propagation delay 34

C.2.7 TCL of cables and channels 34
C.2.8 TCTL of cables and channels 38
C.2.9 Cable and channel measurement precautions 40
C.2.10 Screened or shielded cable and channel measurement configurations 40
C.3 Permanent link test procedures 40
C.3.1 General 40
C.3.2 Permanent link measurement configurations 40
C.3.3 Calibration of permanent link test configurations 41
C.3.4 Return loss of permanent links 41
C.3.5 Insertion loss of permanent link 42
C.3.6 NEXT loss of permanent link 42
C.3.7 FEXT loss of permanent link 43
C.3.8 TCL of permanent link 44
C.3.9 TCTL of permanent link 45
C.3.10 Propagation delay of permanent link 46
C.4 Direct attach measurement procedures 47
C.4.1 Direct attach test configurations 47
C.5 Modular cord test procedures 50
C.5.1 Network analyzer test configuration 50
C.5.2 Test fixturing for modular cords 52
C.5.3 Modular cord measurements 52
C.6 Connecting hardware testing 52
C.6.1 General 52
C.6.2 Connecting hardware measurement configurations 52
C.6.3 Return loss measurements 53
C.6.4 Insertion loss measurements 53
C.6.5 NEXT loss measurements 54
C.6.6 Test plug characterization 56
C.6.7 Category 6A measurement reproducibility 72
C.7 Modular cord test head requirements 74
C.7.1 General 74
C.7.2 Modular cord test head NEXT loss 74
C.7.3 Modular cord test head FEXT loss 74
C.7.4 Modular cord test head return loss 75
C.8 Alien crosstalk measurements 75
C.8.1 Cabling ANEXT loss and AFEXT loss laboratory measurement procedures 75
C.8.2 ANEXT loss and AFEXT loss of cable 77
C.8.3 Connecting Hardware ANEXT loss and AFEXT loss measurements 79
Annex D (normative) Cabling and component balunless test procedures 83
D.1 Balunless measurement requirements 83
D.2 Resistor terminations used with balunless measurement systems 83
D.3 Calibration methods 84
D.4 Testing of cables and cabling 84
D.4.1 Cabling and cable measurement procedures 84
D.4.2 Cabling and cable DC resistance 85
D.4.3 Cabling and cable return loss 85
D.4.4 Insertion loss of cables and channels 86
D.4.5 NEXT loss of cables and channels 87

D.4.6 FEXT loss of cables and channels 87
D.4.7 TCL of cabling and cables 88
D.4.8 TCTL of cabling and cables 88
D.4.9 Propagation delay of cabling and cable 89
D.5 Permanent link test procedures 89
D.5.1 General 89
D.5.2 Permanent link measurement configurations 89
D.5.3 Calibration of permanent link test configurations 89
D.5.4 Return loss of permanent links 89
D.5.5 Insertion loss of permanent link 90
D.5.6 NEXT loss of permanent link 91
D.5.7 FEXT loss of permanent link 92
D.5.8 TCL of permanent link 93
D.5.9 TCTL of permanent link 93
D.5.10 Propagation delay of permanent link 94
D.6 Balunless direct attach measurement procedures 94
D.7 Balunless modular cord test procedures – Balunless network analyzer test configuration 98
D.8 Connecting hardware test procedures 100
D.8.1 General 100
D.8.2 Connecting hardware measurement configurations 100
D.9 Balunless alien crosstalk for cabling, cable and connecting hardware. 101
D.9.1 Balunless ANEXT loss and AFEXT loss laboratory measurement procedures 101
D.9.2 Balunless connecting hardware ANEXT loss and AFEXT loss procedures 101
Annex E (informative) Connecting hardware test fixtures 104
E.1 General 104
E.2 Additional components for connection to a network analyzer 105
E.3 Direct fixture 106
E.4 PCB based test plug assembly 106
E.5 Connecting hardware measurement configuration 107
E.6 Test fixture calibration 108
E.6.1 General 108
E.6.2 Calibration and reference plane location 112
E.7 DUT connections using header PCB assemblies 113
Bibliography 114

Figure B.1 – Example 360° shielded cable termination 16
Figure B 2 – Example individually shielded pair cable termination 17
Figure B.3 – Test fixture interface pattern 17
Figure B.4 – Example pin and socket dimension 18
Figure B.5 – Resistor termination networks for balun testing 19
Figure B.6 – Balunless resistor termination network 20
Figure B.7 – Calibration plane 21
Figure C.1 – Measurement configurations for test balun qualification 26
Figure C.2 – Balun schematic diagram 27
Figure C.3 – Laboratory test configuration for return loss 28

Figure C.4 – Laboratory test configuration for insertion loss and propagation delay measurements 29
Figure C.5 – Laboratory test configuration for cable and channel NEXT loss 31
Figure C.6 – Laboratory test configuration for FEXT loss 33
Figure C.7 – Laboratory test configuration for TCL 35
Figure C.8 – Coaxial lead through calibration 36
Figure C.9 – Back-to-back balun insertion loss measurement 36
Figure C.10 – Output terminal connection 37
Figure C.11 – Outer shield grounding position 37
Figure C.12 – Laboratory test configuration for TCTL 39
Figure C.13 – Laboratory test configuration for permanent link return loss and TCL measurements 41
Figure C.14 – Laboratory test configuration for permanent link insertion loss and propagation delay measurements 42
Figure C.15 – Laboratory test configuration for permanent link NEXT loss measurements 43
Figure C.16 – Laboratory test configuration for permanent link FEXT loss (ACRF) 44
Figure C.17 – Laboratory test configuration for permanent link TCL measurements 45
Figure C.18 – Laboratory test configuration for permanent link TCTL 46
Figure C.19 – Direct attach return loss test configuration 47
Figure C.20 – Direct attach cord insertion loss test configuration 48
Figure C.21 – Direct attach cord NEXT loss test configuration 48
Figure C.22 – Direct attach cord FEXT loss, (ACRF) test configuration 49
Figure C.23 – Direct attach cord TCL test configuration 49
Figure C.24 – Direct attach cord TCTL test configuration 50
Figure C.25 – Modular cord return loss test configuration 51
Figure C.26 – Modular cord NEXT loss test configuration 51
Figure C.27 – Modular cord FEXT loss, (ACRF) test configuration 52
Figure C.28 – Female test connector interface mating dimensions (1) 58
Figure C.29 – Female test connector interface mating dimensions (2) 59
Figure C.30 – Balun fixture PCB paddle card interface mating dimensions 60
Figure C.31 – Balunless fixture PCB paddle card interface mating dimensions 60
Figure C.32 – Example of a measurement setup for test plug NEXT loss 64
Figure C.33 – Example of a measurement setup for test plug FEXT loss 65
Figure C.34 – Direct fixture mating dimensions, top view 67
Figure C.35 – Direct fixture mating dimensions, front view 68
Figure C.36 – Direct fixture mating dimensions, side view 68
Figure C.37 – Modular plug placed into the plug clamp 69
Figure C.38 – Guiding the plug into position 69
Figure C.39 – Calibration planes, test plug phase reference plane, and port extensions 70
Figure C.40 – Examples of direct fixture short, open, load, and through artefacts 72
Figure C.41 – Inter-laboratory return loss variability for testing category 6A connecting hardware 74
Figure C.42 – 6-around-1 cable test configuration 78
Figure C.43 – Connecting hardware ANEXT loss measurement setup 80

Figure C.44 – Connecting hardware AFEXT loss measurement setup 81
Figure C.45 – Example connector configurations for alien crosstalk 82
Figure D.1 – Balunless resistor termination network 84
Figure D.2 – Laboratory test configuration for cabling and cable return loss and TCL measurements 85
Figure D.3 – Laboratory test configuration for cabling and cable insertion loss, TCTL, and propagation delay measurements – Alternate test configuration for return loss and TCL 86
Figure D.4 – Laboratory test configuration for cabling and cable NEXT loss 87
Figure D.5 – Laboratory test configuration for cabling and cable FEXT loss (ACRF) 88
Figure D.6 – Laboratory test configuration for permanent link return loss and TCL measurements 90
Figure D.7 – Laboratory test configuration for permanent link insertion loss, TCTL, and propagation delay measurements – Alternate test configuration for return loss and TCL 91
Figure D.8 – Laboratory test configuration for permanent link NEXT loss measurements 92
Figure D.9 – Laboratory test configuration for permanent link FEXT loss (ACRF) 93
Figure D.10 – Balunless direct attach cord return loss test configuration 95
Figure D.11 – Balunless direct attach insertion loss, TCTL, and propagation delay test configuration – Alternate test configuration for return loss and TCL 96
Figure D.12 – Balunless direct attach cord NEXT loss test configuration 97
Figure D.13 – Balunless direct attach cord FEXT loss, (ACRF) test configuration 98
Figure D.14 – Balunless modular cord NEXT loss test configuration 99
Figure D.15 – Balunless modular cord return loss test configuration 100
Figure D.16 – Connecting hardware ANEXT loss measurement setup 102
Figure D.17 – Connecting hardware AFEXT loss measurement setup 103
Figure E.1 – Test head assembly with baluns attached 104
Figure E.2 – Test head assembly showing shielding between interconnecting sockets 105
Figure E.3 – Plug direct fixture 106
Figure E.4 – PCB based plug 107
Figure E.5 – PCB based plug assembly with adapter 107
Figure E.6 – An example of a connecting hardware measurement configuration 108
Figure E.7 – Test fixture interface 109
Figure E.8 – Open calibration standard applied to balunless test interface 109
Figure E.9 – Short calibration standard applied to balunless test interface 110
Figure E.10 – Load calibration standard applied to test interface 110
Figure E.11 – A loop back through standard applied to a balunless test interface 111
Figure E.12 – Test plug attached to the test interface 111
Figure E.13 – Direct fixture mounted to the test head interface 112
Figure E.14 – Calibration reference plane 112
Figure E.15 – Back-to-back through calibration 113

Table A.1 – IEC 60603-7 series, 8-way connector types detail specifications and respective detail connector test procedures standards 13
Table B.1 – Interconnection return loss 16
Table B.2 – Minimum number of measurement points 19

Table B.3 – Calibration reference load return loss requirement 23
Table C.1 – Test balun performance characteristics 25
Table C.2 – Category 6, 6A and 8 test plug NEXT loss limit vectors 55
Table C.3 – Category 5e test plug NEXT loss limit vectors 55
Table C.4 – Category 6, 6A and 8 connecting hardware NEXT loss requirements for case 1 and case 4 56
Table C.5 – Category 5e, 6, and 6A test plug NEXT loss ranges 62
Table C.6 – Category 8 test plug NEXT loss ranges 63
Table C.7 – Test plug FEXT loss ranges 64
Table C.8 – Category 5e, 6 and 6A test plug return loss requirements 66
Table C.9 – Category 8 test plug return loss requirements 66
Table C.10 – Direct fixture performance 68
Table C 11 – Category 6A NEXT loss measurement reproducibility between laboratories 73
Table C.12 – Category 6A FEXT loss measurement reproducibility between laboratories 73
Table C.13 – Category 5e, 6, and 6A modular cord test head return loss 75
Table C.14 – Category 8 modular cord test head return loss 75

INTERNATIONAL ELECTROTECHNICAL COMMISSION

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CONNECTORS FOR ELECTRICAL AND ELECTRONIC EQUIPMENT – TESTS AND MEASUREMENTS –

Part 27-200: Additional specifications for signal integrity tests up to 2 000 MHz on IEC 60603-7 series connectors – Tests 27a to 27g

FOREWORD

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IEC PAS 60512-27-200 has been processed by subcommittee 48B: Electrical connectors, of IEC technical committee 48: Electrical connectors and mechanical structures for electrical and electronic equipment.

The text of this PAS is based on the following document:	This PAS was approved for publication by the P-members of the committee concerned as indicated in the following document
Draft PAS	**Report on voting**
48B/2652/DPAS	48B/2673/RVDPAS

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A list of all parts of IEC 60512 series, under the general title *Connectors for electrical and electronic equipment – Tests and measurements* can be found on the IEC website.

Future standards in this series will carry the new general title as cited above. Titles of existing standards in this series will be updated at the time of the next edition.

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CONNECTORS FOR ELECTRICAL AND ELECTRONIC EQUIPMENT – TESTS AND MEASUREMENTS –

Part 27-200: Additional specifications for signal integrity tests up to 2 000 MHz on IEC 60603-7 series connectors – Tests 27a to 27g

1 Scope

This part of IEC 60512 covers additional, supplemental specifications for signal integrity and transmission performance test methods of IEC 60512-27-100, for connectors using de-embedded crosstalk measurements, which are specified in respective parts of IEC 60603-7 standards for connecting hardware applications up to 2 000 MHz.

These additional specifications are also applicable for testing the related lower frequency connectors. However, the test methodology specified in the detail specification for any given connector remains the reference conformance test for that connector.

Test procedures of IEC 60512-27-100 affected by these supplemental methods and procedures are:

- insertion loss, test 27a;
- return loss, test 27b;
- near-end crosstalk (NEXT) test 27c;
- far-end crosstalk (FEXT), test 27d;
- transverse conversion loss (TCL), test 27f;
- transverse conversion transfer loss (TCTL), test 27g.

Other test procedures referenced here are:

- transfer impedance (Z_T), see test procedures in IEC 62153-4-6 or IEC 62153-4-7.
- for coupling attenuation (a_C), see test procedures in IEC 62153-4-7 or IEC 62153-4-12.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050-581, *International Electrotechnical Vocabulary (IEV) – Part 581: Electromechanical components for electronic equipment*

IEC 60512-1, *Connectors for electronic equipment – Tests and measurements – Part 1: General*

IEC 60512-26-100, *Connectors for electronic equipment – Tests and measurements – Part 26-100: Measurement setup, test and reference arrangement and measurements for connectors according to IEC 60603-7 – Tests 26a to 26g*

IEC 60512-27-100, *Connectors for electronic equipment – Tests and measurements – Part 27-100: Signal integrity tests up to 500 MHz on 60603-7 series connectors – Tests 27a to 27g*

IEC 60512-28-100, *Connectors for electronic equipment – Tests and measurements – Part 28-100: Signal integrity tests up to 2 000 MHz on IEC 60603-7 and IEC 61076-3 series connectors – Tests 28a to 28g*

IEC 60603-7, *Connectors for electronic equipment – Part 7: Detail specification for 8-way, unshielded, free and fixed connectors*

IEC 60603-7-1, *Connectors for electronic equipment – Part 7-1: Detail specification for 8-way, shielded, free and fixed connectors*

IEC 60603-7-2, *Connectors for electronic equipment – Part 7-2: Detail specification for 8-way, unshielded, free and fixed connectors, for data transmissions with frequencies up to 100 MHz*

IEC 60603-7-3, *Connectors for electronic equipment – Part 7-3: Detail specification for 8-way, shielded, free and fixed connectors, for data transmission with frequencies up to 100 MHz*

IEC 60603-7-4, *Connectors for electronic equipment – Part 7-4: Detail specification for 8-way, unshielded, free and fixed connectors, for data transmissions with frequencies up to 250 MHz*

IEC 60603-7-5, *Connectors for electronic equipment – Part 7-5: Detail specification for 8-way, shielded, free and fixed connectors, for data transmissions with frequencies up to 250 MHz*

IEC 60603-7-41, *Connectors for electronic equipment – Part 7-41: Detail specification for 8-way, unshielded, free and fixed connectors, for data transmissions with frequencies up to 500 MHz*

IEC 60603-7-51, *Connectors for electronic equipment – Part 7-51: Detail specification for 8-way, shielded, free and fixed connectors, for data transmissions with frequencies up to 500 MHz*

IEC 60603-7-81, *Connectors for electronic equipment – Part 7-81: Detail specification for 8-way, shielded, free and fixed connectors, for data transmissions with frequencies up to 2 000 MHz*

IEC 61156-1, *Multicore and symmetrical pair/quad cables for digital communications – Part 1: Generic specification*

IEC 61156-9, *Multicore and symmetrical pair/quad cables for digital communications – Part 9: Cables for channels with transmission characteristics up to 2 GHz – Sectional specification*

IEC 61156-10, *Multicore and symmetrical pair/quad cables for digital communications – Part 10: Cables for cords with transmission characteristics up to 2 GHz – Sectional specification*

IEC 61169-16, *Radio-frequency connectors – Part 16: Sectional specification – RF coaxial connectors with inner diameter of outer conductor 7 mm (0,276 in) with screw coupling – Characteristics impedance 50 ohms (75 ohms) (type N)*

IEC 61935-1, *Specification for the testing of balanced and coaxial information technology cabling – Part 1: Installed balanced cabling as specified in ISO/IEC 11801 and related standards*

IEC 61935-2, *Specification for the testing of balanced and coaxial information technology cabling – Part 2: Cords as specified in ISO/IEC 11801 and related standards*

ISO/IEC 11801-1, *Information technology – Generic cabling for customer premises – Part 1: General requirements*

ITU-T Recommendation G.117, *Transmission aspects of unbalance about earth*